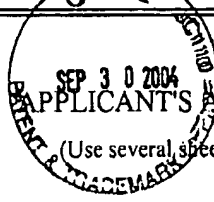
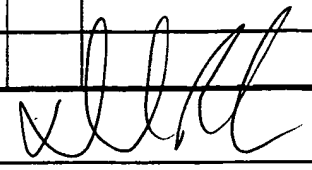
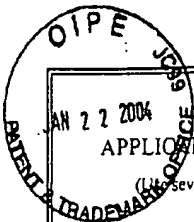


09/914081
518 Ed PCT/PIB 2-2 AUG 2001

APPLICANT'S ART CITATION (Use several sheets if necessary)		Application		OFGS File No. P/25-267 #8		
		Applicant Donald Dominic ARNONE et al.				
		Filing Date		Group Art Unit		
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number				Date	
					Name	
					Class	
					Sub-class	
					Filing Date If Appropriate	
FOREIGN PATENT DOCUMENTS						
	Document Number				Date	
					Country	
					Class	
					Sub-class	
					Translation	
					Yes	No
PCH	0	8	4	1	5	4
	8	05/13/98	Europe			
	0	8	2	8	1	4
	3	03/11/98	Europe			
	0	7	2	7	6	7
	1	08/21/96	Europe			
	0	8	6	4	8	5
	7	09/16/98	Europe			
PCH	2	2	5	4	4	1
	7	10/07/92	Great Britain			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
PCH	WU Q ET AL: "TWO-DIMENSIONAL ELECTRO-OPTIC IMAGING OF THZ BEAMS"					
	APPLIED PHYSICS LETTERS, US, AMERICAN INSTITUTE OF PHYSICS. NEW YORK					
	vol. 69, no. 8, 19 August 1996 (1996-08-19), pages 1026-1028, XP000626128					
	ISSN: 0003-6951					
	PATENT ABSTRACTS OF JAPAN					
	vol. 13, no. 182 (C-591), 27 April 1989 (1989-04-27)					
	& JP 01 011530 A (HITACHI), 17 January 1989 (1989-01-17)					
PCH	Abstract					
Examiner	Date Considered				5-2-2004	
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						

Best Available Copy

		Application 09/914,081		OFGS File No. P/25-267			
		Applicant Donald Dominic ARNONE, et. al.					
		Filing Date August 22, 2001		Group Art Unit 3742			
U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
PCA		IEEE Journal of Selected Topics in Quantum Electronics, Vol. 2, No. 3, September 1996,					
PCA		pages 679-692: T-Ray Imaging, Daniel M. Mittleman, et. al. - XP 000689828					
Examiner			Date Considered 5-2-2006				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							



APPLICANT'S ART CITATION (If several sheets if necessary)		Application 09/914,081		OFGS File No. P/25-267			
		Applicant Donald Dominic ARNONE et al.					
		Filing Date April 23, 2002		Group An Unit 2882			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
<i>DLR</i>	US-5,789,750	08-1998	Nuss	250	338.1	RECEIVED JAN 28 2004 TECHNOLOGY CENTER R3700	
<i>DLR</i>	US-5,623,145	04-1997	Nuss	250	330		
<i>DLR</i>	US-5,710,430	01-1998	Nuss	250	358.1		
	US-						
	US-						
	US-						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
<i>DLR</i>	WO 97/45747	12-1997	PCT			Yes	No
<i>DLR</i>	EP 0 841 548 A2	05-1998	EPO				
<i>DLR</i>	EP 0 828 162 A2	03-1998	EPO				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>DLR</i>	1.	Fattinger, et al., "Point Source Terahertz Optics" Appl. Phys. Lett. 53(16), 17 October 1988, pp. 1480-1482.					
	2.	Fattinger et al., "Tetahertz Beams" Appl. Phys. Lett. 54 (6), 6 February 1989, pp. 490-492					
	3.	Mittleman, et al. "T-Ray Imaging" IEEE Journal of Selected Topics in Quantum Electronics, 2 (3), September 1996, pp. 679-692.					
<i>DLR</i>	4.	Zamdmer et al., "On-Chip Frequency-Domain Submillimeter-Wave Transceiver" Appl. Phys. Lett. 75 (24), 12 December 1999, pp. 3877-3879.					
Examiner	<i>DLR</i>		Date Considered		5-2-2005		
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							